

INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(Multiple sheets used when necessary)</i>	Application No.	10/815,905
	Filing Date	March 31, 2004
	First Named Inventor	Lin et al.
	Art Unit	2874
SHEET 1 OF 2		Examiner Hoang Q. Tran
		Attorney Docket No. QCO.094A/061113

U.S. PATENT DOCUMENTS

Examiner Initials	Cite No.	Document Number Number - Kind Code (if known) Example: 1,234,567 B1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear
	1	4,863,245	9/5/1989	Roxlo	
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	11	6,549,195	4/15/2003	Hikida et al.	
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	19	2002-0167072	11/14/2002	Andosca	
	20	2002-0171610	11/21/2002	Siwinski et al.	
	21	2002-0186209	12/12/2002	Cok	
	22	2003-0053078	3/20/2003	Missey et al.	
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	25	2004-0100594	5/27/2004	Huibers et al.	

Examiner Signature	Date Considered
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FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.	Foreign Patent Document Country Code-Number-Kind Code Example: JP 1234567 A1	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear	T ¹
	26	CH 680534	9/15/1992	Landis & GYR Betriebs AG		X-abstract
	27	EP 1 170 618	1/9/2002	Sony Corp		
	28	JP 2003195201	7/9/2003	Fuji Photo Film Co		X
	29	WO 03/046508	6/5/2003	Biomicroarrays		
	30	WO 04/000717	12/31/2003	Filtronic		
	31	WO 04/015741	2/19/2004	Unaxis USA		

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ¹
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